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Application/Control No.	Applicant(s)/Patent under Reexamination
10/051,267	TANAKA ET AL.
Examiner	Art Unit
Thien F Tran	2811

	SEARCHED				
Class	Subclass	Date	Examiner		
257	59, 66	2/18/2005	П		
257	70, 72	2/18/2005	ΤΤ		
257	75	2/18/2005	ΤΤ		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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